

SYSTEMC AMS DAY 2011

INDUSTRY ADOPTION OF THE SYSTEMC AMS STANDARD

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SystemC AMS Day 2011 **Industry Adoption of** the SystemC AMS **Standard**

May 12, 2011 Dresden

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SYNOPSYS°





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State of the Art, Related Work

Mainstream tries to use RT/circuit level models and simulation

- Mixed-Level, Multi-Run, Monte-Carlo, etc.
- Design of Experiments [Rafaila]
- Earlier estimation of power + accuracy needed!

SystemC AMS Methodology enables modeling and simulation of embedded mixed-signal systems at functional, architecture level.

- Power consumption?
- Accuracy?

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Overview

- Introduction
- Refinement methodology
- MARC/SYCYPHOS Design environment, examples
- Future work









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tools and libraries based on SystemC

=> Accuracy budgeting

=> Power budgeting





TDF: Filter in Receiver SCA TDF MODULE(lp filter tdf) { sca_tdf::sca_in<AAF> in; sca_tdf::sca_out<AAF> out; sca tdf::sca in<AAF> gain; sca tdf::sca ltf nd ltf; sca util::sca vector<double> num, den; // coefficients void initialize() { num(0) = 1.0;den(0) = 1.0; den(1) = 1.0/(2.0*M_PI*1.0e4); } void processing() out.write(ltf(num, den, in.read() * gain.read()) + noise()); } SCA_CTOR(lp_filter_tdf) {} }; TU Institute of

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Accuracy Profiling and Iterative Refinement







Affine Arithmetic [Andrade et al.] Improves Interval Arithmetics by conserving *correlations* in a symbolic way Affine Arithmetics represents a size \hat{x} by • an ideal, numerical 'central value' x_0 , and • *n* partial deviations x_i scaled by noise symbols $\epsilon_i \in [-1, 1]$ $\hat{x} = x_0 + \sum_{i=1}^n x_i \epsilon_i$ Institute of TU Computer Technology **Graphical representations** $\hat{y}(t)$ ŷ(t) ▲ Range based system response Institute of τIJ computer Technology





Libraries & Tools

1. Library of functional blocks

- Blocks for receiver/transmitter (serializer, modulators, mixers, ACD, ...)
- Non-ideal properties (Noise, offset, nonlinearities, ...)
- Models von processors (ISS)

2. Profiling tools

- Accuracy profiling
- Power (see poster)





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sink nodes

runtime

Conclusion, Outlook

- Range based refinement methodology
 - Complements Worst-Case Analysis
 - Single run, traceable deviations influence
 - Refinement information = recommendations, maybe automation?
- Planned extensions
 - Automated management of ressource "accuracy"
 - "Expert-models" that include typical risks as kind of IP-Knowledge from recent projects

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Future work: SYCYPHOS/MARC



- Modeling of scenarios and high-level communication in cyber and physical worlds
- Modeling of accuracy, robustness, power consumption in microelectronic systems
- Challenge: Automatical analysis, verification, and improvement of accuracy, resilience/adaptivity, power consumption



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Affine Arithmetic: Syster

System Simulation, SystemC AMS

Directed signal flow; output = f(input, state)

Models of Computation: Synchronous & Dynamic Data flow, KPN, Discrete event modeling, Signal flow

System Simulation with AA straight forward:

Class library provides abstract data type AAF and associated linear and nonlinear operations

Number of noise terms increases with each nonlinear operations \rightarrow "Garbage collection"





m Simulation

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Circuit Simulation with Affine Arithmetic



Computation of Affine ASPs

Computaton of Affine ASP as follows:

- **1.** Compute x_0 by existing Newton-Raphson iteration: $\underline{F}(\underline{x}_0, p_0, t) = \underline{0} \quad \rightarrow \quad \hat{\underline{x}} = \underline{x}_0$
- 2. Compute $x_i \epsilon_i$ by sensitivity analysis:
- 3. Compute $NL \in \epsilon_{i+1}$ (in n-dim space) by approximation scheme in vector/matrix form (Grabowski 2006, 2007, 2008).

$$\underline{\hat{x}} = \underline{x}_0 + \sum \underline{x}_p \epsilon_p + \underline{x}_{ep}$$

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 $\mathbf{J}|_{x_0,p_0} \Delta \underline{x} + \mathbf{P}|_{x_0,p_0} \Delta p = \underline{0} \quad \rightarrow \quad \underline{\hat{x}} = \underline{x}_0 + \sum \underline{x}_p \epsilon_p$

 $d^{\epsilon}epd,i$

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